

### **IGBT Modules**

#### **SKM 400GA123D**

#### **Features**

- MOS input (voltage controlled)
- N channel, homgeneous Si
- · Low inductance case
- Very low tail current with low temperature dependence
- High short circuit capability, self limiting to 6 x I<sub>cnom</sub>
- · Latch-up free
- Fast & soft inverse CAL diodes
- Isolated copper baseplate using DBC Direct Copper Bonding Technology
- Large clearance (12 mm) and creepage distances (20 mm)

### **Typical Applications**

• Switching (not for linear use)

<b>Absolute Maximum Ratings</b> $T_c = 25  ^{\circ}C$ , unless otherwise specified					
Symbol	Conditions		Values	Units	
IGBT					
$V_{CES}$	T <sub>j</sub> = 25 °C		1200	V	
I <sub>C</sub>	T <sub>j</sub> = 150 °C	T <sub>case</sub> = 25 °C	400	Α	
		T <sub>case</sub> = 80 °C	360	Α	
I <sub>CRM</sub>	I <sub>CRM</sub> =2xI <sub>Cnom</sub>		600	Α	
$V_{GES}$			± 20	V	
t <sub>psc</sub>	$V_{CC}$ = 600 V; $V_{GE} \le 20$ V; VCES < 1200 V	T <sub>j</sub> = 125 °C	10	μs	
Inverse D	iode				
I <sub>F</sub>	T <sub>j</sub> = 150 °C	$T_{case}$ = 25 °C	390	Α	
		T <sub>case</sub> = 80 °C	260	Α	
I <sub>FRM</sub>	I <sub>FRM</sub> =2xI <sub>Fnom</sub>		600	Α	
I <sub>FSM</sub>	t <sub>p</sub> = 10 ms; sin.	T <sub>j</sub> = 150 °C	2880	Α	
Module					
I <sub>t(RMS)</sub>			500	Α	
$T_{vj}$			- 40+ 150	°C	
T <sub>stg</sub>			- 40+ 125	°C	
V <sub>isol</sub>	AC, 1 min.		2500	V	

Characteristics T <sub>c</sub> =			25 °C, unless otherwise specified			
Symbol	Conditions		min.	typ.	max.	Units
IGBT						
$V_{GE(th)}$	$V_{GE} = V_{CE}$ , $I_C = 12 \text{ mA}$		4,5	5,5	6,5	V
I <sub>CES</sub>	$V_{GE} = 0 V, V_{CE} = V_{CES}$	T <sub>j</sub> = 25 °C		0,1	0,3	mA
V <sub>CE0</sub>		T <sub>j</sub> = 25 °C		1,4	1,6	V
		T <sub>j</sub> = 125 °C		1,6	1,8	V
$r_{CE}$	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25°C		3,66	4,66	mΩ
		T <sub>j</sub> = 125°C		5	6,33	mΩ
$V_{\text{CE(sat)}}$	I <sub>Cnom</sub> = 300 A, V <sub>GE</sub> = 15 V	$T_j = {^{\circ}C_{chiplev.}}$		2,5	3	V
C <sub>ies</sub>				22	30	nF
C <sub>oes</sub>	$V_{CE} = 25, V_{GE} = 0 V$	f = 1 MHz		3,3	4	nF
C <sub>res</sub>				1,2	1,6	nF
$Q_G$	V <sub>GE</sub> = -8V - +20V			3000		nC
$R_{Gint}$	T <sub>j</sub> = °C			1,25		Ω
t <sub>d(on)</sub>				200	400	ns
t <sub>r</sub>	$R_{Gon}$ = 3,3 $\Omega$	V <sub>CC</sub> = 600V		115	220	ns
E <sub>on</sub>		I <sub>Cnom</sub> = 300A		38		mJ
$t_{d(off)}$	$R_{Goff}$ = 3,3 $\Omega$	T <sub>j</sub> = 125 °C		720	900	ns
t <sub>f</sub>		$V_{GE} = \pm 15V$		80	100	ns
$E_{off}$				40		mJ
$R_{th(j-c)}$	per IGBT				0,045	K/W





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• Switching (not for linear use)

Character	ristics					
Symbol	Conditions		min.	typ.	max.	Units
Inverse D						
$V_F = V_{EC}$	$I_{Fnom} = 300 \text{ A}; V_{GE} = 0 \text{ V}$			2	2,5	V
		$T_j = 125 ^{\circ}\text{C}_{\text{chiplev.}}$ $T_j = 25 ^{\circ}\text{C}$		1,8		V
$V_{F0}$				1,1	1,2	V
		T <sub>j</sub> = 125 °C				V
r <sub>F</sub>		T <sub>j</sub> = 25 °C		3	4,3	mΩ
		T <sub>j</sub> = 125 °C T <sub>j</sub> = 25 °C				mΩ
I <sub>RRM</sub>	I <sub>Fnom</sub> = 300 A	T <sub>j</sub> = 25 °C		85		Α
Q <sub>rr</sub>	di/dt = 2000 A/μs			13		μC
E <sub>rr</sub>	V <sub>GE</sub> = 0 V; V <sub>CC</sub> = 600 V					mJ
$R_{th(j-c)D}$	per diode				0,125	K/W
Freewhee	ling Diode					
$V_F = V_{EC}$	$I_{Fnom} = A; V_{GE} = V$	$T_j = {^{\circ}C_{chiplev.}}$				V
V <sub>F0</sub>		$T_{j} = {^{\circ}C_{chiplev.}}$ $T_{j} = 25 {^{\circ}C}$				V
		T <sub>j</sub> = 125 °C				V
$r_F$		T <sub>j</sub> = 25 °C				V
		T <sub>j</sub> = 125 °C				V
I <sub>RRM</sub>	I <sub>Fnom</sub> = A	T <sub>j</sub> = °C				A
Q <sub>rr</sub>	N 0 N N 000 N					μC
E <sub>rr</sub>	V <sub>GE</sub> = 0 V; V <sub>CC</sub> = 600 V					mJ
	per diode					K/W
Module			i			
L <sub>CE</sub>				15	20	nΗ
R <sub>CC'+EE'</sub>	res., terminal-chip	T <sub>case</sub> = 25 °C		0,18		mΩ
		T <sub>case</sub> = 125 °C		0,22		mΩ
R <sub>th(c-s)</sub>	per module				0,038	K/W
M <sub>s</sub>	to heat sink M6		3		5	Nm
M <sub>t</sub>	to terminals M6 (M4)		2,5 (1,1)		5 (2)	Nm
w					330	g

This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, Chapter IX.

This technical information specifies semiconductor devices but promises no characteristics. No warranty or guarantee expressed or implied is made regarding delivery, performance or suitability.





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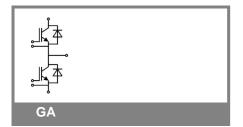
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Feature	28
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Switching (not for linear use)



Z <sub>th</sub> Symbol	Conditions	Values	Units
Z,,,,,,,,,	•		
Z <sub>Ri</sub>	i = 1	33	mk/W
R <sub>i</sub>	i = 2	8,8	mk/W
R <sub>i</sub> R <sub>i</sub>	i = 3	2,6	mk/W
R <sub>i</sub>	i = 4	0,6	mk/W
tau <sub>i</sub>	i = 1	0,05	S
tau <sub>i</sub>	i = 2	0,009	s
tau <sub>i</sub>	i = 3	0,0024	s
tau <sub>i</sub>	i = 4	0,0001	s
Z <sub>th(j-c)D</sub>			
R <sub>i</sub>	i = 1	85	mk/W
R <sub>i</sub>	i = 2	31	mk/W
$R_{i}$	i = 3	7,8	mk/W
R <sub>i</sub>	i = 4	1,2	mk/W
tau <sub>i</sub>	i = 1	0,0537	s
tau <sub>i</sub>	i = 2	0,0086	s
tau <sub>i</sub>	i = 3	0,003	s
tau <sub>i</sub>	i = 4	0,0001	s

